## Application/Control No. Applicant(s)/Patent Under Reexamination 10/754,815 NAKAYA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2618 Nhan T. Le

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,509,872	01-2003	Ishii et al.	342/383
*	В	US-2002/0085653	07-2002	Matsuoka et al.	375/347
*	С	US-7,006,553	02-2006	McCorkle, John W.	375/130
*	D	US-2002/0190900	12-2002	Kimata et al.	342/368
•	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	ÜS-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.